

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	452	cluster near length	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/14 14:01
L2	12	cluster\$3 near flip?flop	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/14 14:02
L3	33	cluster\$3 adj4 flip?flop	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/14 14:02
L4	4	1 and 3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/14 14:05
L5	739	insert\$3 adj4 flip-flop	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/14 14:05
L6	3	4 and 5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/14 14:06
L7	63011	measur\$3 adj4 length	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/14 14:07
L8	1	6 and 7	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/14 14:07

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S1	1540	cluster adj5 length	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/09/14 14:00
S2	179	cluster adj length	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/10 17:05
S3	527830	optimiz\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/10 16:59
S4	39	S2 and S3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/10 16:59
S5	1	(cluster adj length) near insert\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/10 17:02
S6	1	(cluster\$3 adj length) near insert\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/10 17:03
S7	4	(cluster\$3 adj length) near predetermined	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/10 17:03
S8	1	group\$3 near length near insert\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/10 17:16

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S9	77	(re-cluster\$3 or recluster\$3 or regroup\$3 or repartition\$3) and insert\$3 and (flip-flop)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/10 17:17
S10	411	(re-cluster\$3 or recluster\$3 or regroup\$3 or repartition\$3) and insert\$3 and (flip-flop or register)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/10 17:18
S11	166	S3 and S10	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/10 17:18
S12	3862554	length	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/10 17:18
S13	144	S11 and S12	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/11 07:31
S14	1687	(716/2,7).ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/11 07:31

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Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	(optimiz\$5 and cluster\$3 and flip-flip and insert\$3 and re-cluster\$3 and length).clm.	US-PGPUB; USPAT	OR	ON	2006/09/14 14:09



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- IEE JNL IEE Journal or Magazine
- IEEE CNF IEEE Conference Proceeding
- IEE CNF IEE Conference Proceeding
- IEEE STD IEEE Standard

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IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

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IEEE STD IEEE Standard

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